Sheet 1 of 2 sheet(s)

U.S. Department of Commerce, Patent	Docket No.	Serial No.	
(PTO Form 1449 modified)	7954/DSM/BCVD/JW	10/697,731	
INFORMATION DISCLOSURE STATE	Applicant Yim, et al.	Confirmation No.:	
(Use several sheets if necessary)	s mm &	Filing Date	Group
Examiner	Marc	October 29, 2003	3661
	TEL MILE.		

	T	Examiner	e thrance	C . F	October	29, 2003	366	<b>]</b> .
			A TRA	Men of Fr.				
J.S. Paten	t Docu	ments	A TRA		1		•	
'Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date Appropriate	
n • m	A1	2002/0078770	06/27/2002	Hunter	73	865.9		
	A2	2002/0092369	07/18/2002	Hunter	73	865.9		
	А3	2002/0101508	08/01/2002	Pollack	348	85		
	A4	2003/0001083	01/02/2003	Corrado et al.	250	239		
	A5	2003/0198376	10/23/2003	Sadighi et al.	382	153		
	A6	2003/0202092	10/30/2003	Sadighi et al.	348	87		
1	A7	4,819,167	04/04/1989	Cheng, et al.	364	167.01		
	A8	5,452,521	09/26/1995	Niewmierzycki	33	520		_
	A9	5,483,138	01/09/1996	Shmookler, et al.	318	568.16		
	A10	5,844,683	12/01/1998	Pavloski, et al.	356	399		
	A11	5,917,601	06/29/1999	Shimazaki, et al.	356	375		
	A12	5,980,194	11/09/1999	Freerks, et al.	414	754		
	A13	6,002,840	12/14/1999	Hofmeister	395	80		
	A14	6,051,113	04/18/2000	Moslehi	204	192.12		
	A15	6,198,976 B1	03/06/2001	Sundar, et al.	700	59		
	A16	6,244,121 B1	06/12/2001	Hunter	73	865.9		
	A17	6,313,596 B1	11/06/2001	Wyka, et al.	318	640		
	A18	6,468,816 B2	10/22/2002	Hunter	438	14		
-	A19	6,648,730	11/18/2003	Chokshi et al.	451	6		
								-
Foreign Pa	itent D	ocuments						
*Examiner Initial		Document	Date	Country	Class	Subclass	Transl	ation
		Number ————————————————————————————————————					YES	NO
	B1							
	B2							
	В3							
	B4							

Sheet 2 of 2 sheet(s)

						neet 2 of 2 sneet(s)	
U.S. Department of Commerce, Patent and Trademark Office			Docket No.	Serial No.			
(PTO Form 1449 modified)			7954/DSM/BCVD/JW	10/697,731			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT			Applicant Yim, et al.	Confirmation No.:			
(Use several sheets if necessary)			Filing Date	Group			
·		Examiner .	Ma	EJAN 15 Mar	October 29, 2003	3661	
			_	2			
OTHER AR	RT.	,	· <del></del>	TA TRADE			
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.					
m•m	C1	"Wafercam <sup>tm</sup> System: Wireless Camera System for Semiconductor Processing Robotic Arm Calibration", <a href="https://www.gtweed.com/semiconductor/Wafercam.htm">www.gtweed.com/semiconductor/Wafercam.htm</a> , printed 12/10/2002					
	C2						
	С3						
Examiner	<b>W</b> )	cDieune	L ~~	اعمد	Date Considered 10	0-06-05	
*EXAMINER	: Initia	Lif reference considered	d, whether		ormance with MPEP 609; Divith your communication to		